



Sheet 1 of 2

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO.		SERIAL NO.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				11157-23		09/854,905	
				APPLICANT .			
(Use several sheets If necessary)				BRIAN MOORE			
			FIL	ING DATE	GRO	JP	
				61.			
			Ma	y 15, 2001	2858		
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	DOCUMENT			6 01 R 31	28	Not needed
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	C mplet if Known		
Application Number	09/854,905		
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First Named Inventor	MOORE, Brian		
Group Art Unit	2829		
Examiner Name	N/A		
Attorney Docket Number	11157-23		
	Application Number Filing Date First Named Inventor Group Art Unit	Application Number 09/854,905 Filing Date May 15, 2001 First Named Inventor MOORE, Brian Group Art Unit 2829 Examiner Name N/A	

		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Examiner	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T2
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